


<b>Search Notes</b>  	<b>Application/Control No.</b>  10725378	<b>Applicant(s)/Patent Under Reexamination</b>  FAN ET AL.
	<b>Examiner</b>  PETER COUGHLAN	<b>Art Unit</b>  2129

SEARCHED			
Class	Subclass	Date	Examiner
706	@pd<20031203 and 8, 16, 45, 49	11/2/2007	PDC
703	@pd<20031203 and 2, 9	11/2/2007	PDC
706	@ad<20031203 and @pd>20071102 w/45, 46, 12, 16	4/29/2008	PDC
706	@ad<20031203 and 46	7/14/2008	PDC
707	@ad<20031203 and 1, 3, 4	7/14/2008	PDC
706	Apd<20031203 with model and 12, 16, 21	12/4/2008	PDC

SEARCH NOTES		
Search Notes	Date	Examiner
East -- @pd<20031203 and inductive learning, learning model, featrure vector, aggregate benefit, application, purpose, function, Fan Wei, Wang Haixun, Yu Phillip, database, segment, subset, accuracy, predictive, time, cost, stepwise, progressive	11/2/2007	PDC
IEEE -- <2003 Fan Wei, Wang Haixun, Yu Phillip, database, subset, accuracy, predictive, time, cost, stepwise, progressive, inductive learning, learning model, feature vector, aggregae benefit, application, purpose, function	11/2/2007	PDC
Inventors -- Fan Wei, Wang Haixun, Yu Phillip	11/2/2007	PDC
Google <2003 inductive learning, learning model, feature vector, aggregae benefit, application, purpose, function, Fan Wei	11/2/2007	PDC
Dogpile Fan Wei, Wang Haixun, Yu Phillip, database, segment, subset, accuracy, predictive, time cost stepwise, progressive	11/2/2007	PDC
East -- @ad<20031203 and @pd>20071102 and dataset, subset, learning model, model, plurality w/subset, increment, divid\$, database, progressive, termination, threshold, build\$, combin\$	4/29/2008	PDC
East -- @pd<20031203 and inductive, learning model, dividing, dataset, data, subset, model, indication w/termination, threshold, accuracy, current	12/4/2008	PDC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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